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layer 19 remains present. This makes it easier to observe the marker 23 through the light receiving element, despite that 23 the marker 32 on the optical device is shadowed by the edge emitting/incidence type light receiving element, thereby enhancing the production efficiency.

Page 12, please amend the paragraph beginning at line 3 as follows:

The marker 23 is measured based on a difference between an amount of light transmitting through the non-transmitting portion at the edge thereof and an amount of light transmitting through the transmitting portion at the edge thereof when the detection light is irradiated at the time of positioning. However, the transmitting portion does not permit all of the incident light to pass through but attenuates a part thereof. Here, assuming that a value of the contrast at the time when all of the incident light passes through is equal to 100%, the luminance distribution in the case of the contrast of 30% is as illustrated in FIG. 2.

IN THE CLAIMS:

Please amend claims 1, 7 and 10-14 as follows:

1. (amended) A semiconductor light receiving element having a light absorbing layer on a plane generally parallel to a plane with which said element is mounted on a substrate,

